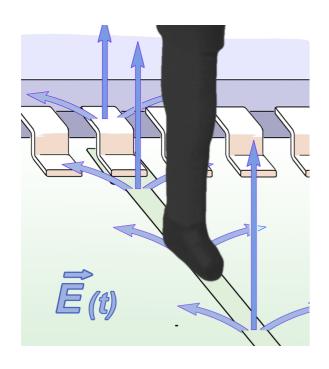
### RF-E 05 E-Field Probe 30 MHz up to 3 GHz





#### Short description

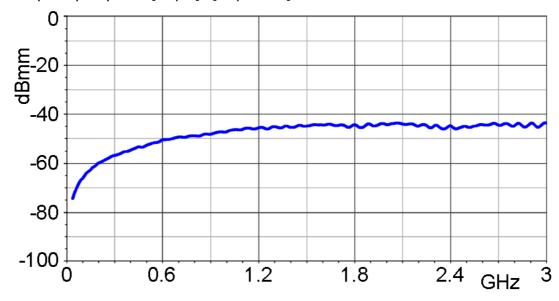
The electrode at the underside of the probe head of the RF-E 05 has a width of approx. 0.5 mm. The E-fields of clocked lines, IC pins, and smaller components are precisely located. The RF-E 05 probe was developed for Langer scanner.

The RF-E 05 is a near-field probe. It has the same structure as the RF-E 02 and RF-E 10 probes, but detects E-fields from very small ranges. The RF-E 05 is designed to detect the specific cause of an electrical interference field. For measurements the E-field probe is positioned directly onto or held above the components or surfaces of printed circuit boards. The near-field probe is small and handy. It has a current attenuating sheath and, therefore, is electrically shielded. It can be connected to a spectrum analyzer or an oscilloscope with a 50  $\Omega$  input. The H-field probe does not have an internal terminating resistance of 50  $\Omega$ .

#### Technical parameters

Frequency range	30 MHz 3 GHz
Resolution	≈ 0.6 mm
Probe head dimensions	≈ (1 x 8) mm
Connector - output	SMB, male, jack

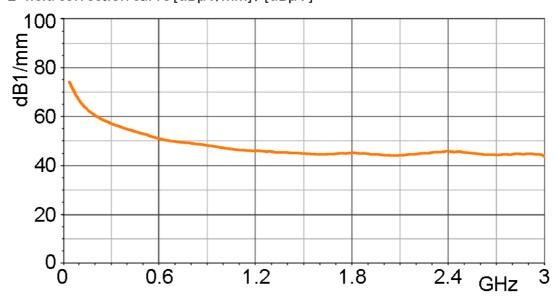
#### Frequency response [dBµV] / [dBµV/mm]



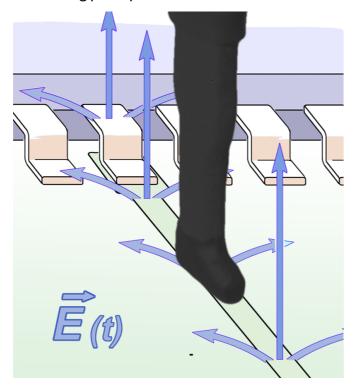
## RF-E 05 E-Field Probe 30 MHz up to 3 GHz



### E- field correction curve [dB $\mu$ V/mm] / [dB $\mu$ V]



### Measuring principles



# RF-E 05 E-Field Probe 30 MHz up to 3 GHz



#### Probe head

